

Editorial

Volume 10 of *Microscopy and Microanalysis* marks this journal's tenth year. The stated aim of the journal remains to provide a forum for original research papers dealing with new microscopy and microanalysis techniques and their applications. Papers are indexed in several databases including MEDLINE(PubMed) and Chemical Abstracts. Also provided are book reviews and a comprehensive calendar of microscopy events. The journal title is owned by the Microscopy Society of America, and the publisher is Cambridge University Press. The journal now ranks among the top microscopy journals in the world. This achievement is directly attributable to the efforts of its many editors, editorial board members, authors, and reviewers. Particularly notable is the work of my two predecessors, Jean-Paul Revel and Dale Johnson. I thank you all.

The popularity of the journal has increased steadily over the last few years. There is now considerable competition for space in these pages. In fact, every page allocated to scientific content is used and then some. For 2004, Cambridge University Press has redesigned the page layout with a tighter line spacing, allowing additional papers to be printed. In addition, proofed papers in final form are now available for viewing and citing, ahead of the printing schedule, at the Cambridge Journals Online website: <http://www.journals.cambridge.org>. All subscribers have access to back issues of *Microscopy and Microanalysis* through this service. See instructions on the cover sheet that came with your copy of the journal.

This issue contains two special sections. One group of papers is from the Ernst Ruska-Centre for Microscopy and Spectroscopy with Electrons at the Research Centre Jülich Ltd., Germany. These papers show the power of quantitative transmission electron microscopy, particularly when combined with correction for spherical aberration. The second special section contains papers from Argentina, Brazil, and Venezuela. These papers were submitted in conjunction with the 7th InterAmerican Congress on Electron Microscopy held in San Antonio, Texas, in August 2003.

Charles E. Lyman
Editor in Chief